

*“Application of auxiliary signals in X-ray fluorescence and electron microprobe analysis for density evaluation”*. Kuczumov A, Vekemans B, Schalm O, Vincze L, Dorriné W, Gysels K, Van Grieken R, X-ray spectrometry **28**, 282 (1999). [http://doi.org/10.1002/\(SICI\)1097-4539\(199907/08\)28:4<282::AID-XRS352>3.0.CO;2-H](http://doi.org/10.1002/(SICI)1097-4539(199907/08)28:4<282::AID-XRS352>3.0.CO;2-H)